

10583660_CLSTI TLES

Titles of most frequently occurring classifications of patents returned from a search of 10583660 on Apr 20 , 2009

- 4 430/ 5 (4 OR, 0 XR)
Class 430 RADI ATI ON I MAGERY CHEM STRY: PROCESS, COMPOSI TI ON, OR
PRODUCT THEREOF
430/ 4 . RADI ATI ON MODI FYI NG PRODUCT OR PROCESS OF MAKI NG
430/ 5 .. Radi ation mask
- 4 250/ 492. 2 (1 OR, 3 XR)
Class 250 RADI ANT ENERGY
250/ 492. 1 . I RRADI ATI ON OF OBJECTS OR MATERI AL
250/ 492. 2 .. Irradi ation of semi conductor devi ces
- 4 382/ 141 (3 OR, 1 XR)
Class 382 I MAGE ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manufacturing or product i nspection
- 3 250/ 491. 1 (2 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 491. 1 . MEANS TO ALI GN OR POSI TI ON AN OBJECT RELATI VE TO A SOURCE
OR DETECTOR
- 3 356/ 71 (2 OR, 1 XR)
Class 356 OPTI CS: MEASURI NG AND TESTI NG
356/ 71 . DOCUMENT PATTER N ANALYSI S OR VERI FI CATI ON
- 2 382/ 147 (1 OR, 1 XR)
Class 382 I MAGE ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manufacturing or product i nspection
382/ 145 ... I nspection of semi conductor devi ce or printed circuit
board
382/ 147 I nspecting printed circuit boards
- 2 382/ 149 (1 OR, 1 XR)
Class 382 I MAGE ANALYSI S
382/ 100 . APPLI CATI ONS
382/ 141 .. Manufacturing or product i nspection
382/ 145 ... I nspection of semi conductor devi ce or printed circuit
board
382/ 149 Fault or defect detection
- 2 348/ 126 (0 OR, 2 XR)
Class 348 TELEVI SI ON
348/ 61 . SPECI AL APPLI CATI ONS
348/ 125 .. Fl aw detect or
348/ 126 ... Of electronic circuit chip or board
- 2 250/ 310 (1 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 306 . I NSPECTI ON OF SOLI DS OR LI QUI DS BY CHARGED PARTI CLES
250/ 310 .. Electron probe type
- 2 250/ 307 (1 OR, 1 XR)
Class 250 RADI ANT ENERGY
250/ 306 . I NSPECTI ON OF SOLI DS OR LI QUI DS BY CHARGED PARTI CLES
250/ 307 .. Met hods
- 2 430/ 322 (0 OR, 2 XR)
Class 430 RADI ATI ON I MAGERY CHEM STRY: PROCESS, COMPOSI TI ON, OR

PRODUCT THEREOF

430/269 . IMAGI NG AFFECTI NG PHYSI CAL PROPERTY OF RADI ATI ON SENSITI VE
 MATERI AL, OR PRODUCI NG NONPLANAR OR PRI NTI NG SURFACE - PROCESS, COMPOSITI ON, OR
 PRODUCT

430/322 .. Formi ng nonpl anar surface

2 714/720 (2 OR, 0 XR)

Class 714 ERROR DETECTI ON/ CORRECTI ON AND FAULT DETECTI ON/ RECOVERY

714/699 . PULSE OR DATA ERROR HANDLI NG

714/718 .. Memory testing

714/719 ... Read-in with read-out and compare

714/720 Special test pattern (e.g., checker board, wal king ones)

2 365/200 (0 OR, 2 XR)

Class 365 STATI C I NFORMATI ON STORAGE AND RETRI EVAL

365/189.011 . READ/ WRI TE CI RCUI T

365/200 .. Bad bit

2 714/766 (0 OR, 2 XR)

Class 714 ERROR DETECTI ON/ CORRECTI ON AND FAULT DETECTI ON/ RECOVERY

714/699 . PULSE OR DATA ERROR HANDLI NG

714/746 .. Di gital data error correction

714/752 ... Forward correction by block code

714/763 Memory access

714/766 Check bits stored in separate area of memory

2 714/E11.036 (0 OR, 2 XR)

Class 714 ERROR DETECTI ON/ CORRECTI ON AND FAULT DETECTI ON/ RECOVERY

714/E11.001 . ERROR DETECTI ON; ERROR CORRECTI ON; MONI TORI NG (EPO)

714/E11.021 .. Respondi ng to the occurrence of a fault, e.g., fault
 tolerance, etc. (EPO)

714/E11.03 ... Error detection or correction by redundancy in data
 representation, e.g., by using checking codes, etc. (EPO)

714/E11.032 Adding special bits or symbols to the coded information,
 e.g., parity check, casting out 9's or 11's, etc. (EPO)

714/E11.034 In memories (EPO)

714/E11.035 In static stores (EPO)

714/E11.036 Integrated on a chip (EPO)

2 714/805 (0 OR, 2 XR)

Class 714 ERROR DETECTI ON/ CORRECTI ON AND FAULT DETECTI ON/ RECOVERY

714/699 . PULSE OR DATA ERROR HANDLI NG

714/799 .. Error/fault detection technique

714/800 ... Parity bit

714/805 Storage accessing (e.g., address parity check)

2 365/201 (0 OR, 2 XR)

Class 365 STATI C I NFORMATI ON STORAGE AND RETRI EVAL

365/189.011 . READ/ WRI TE CI RCUI T

365/201 .. Testi ng